

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0088677	05-2004	Williams, Clay Edwin	717/104
*	В	US-6,321,376	11-2001	Willis et al.	717/124
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	A UML-Based Approach to System Testing. Lional Briand, Y van Labiche. Software Quality Engineering Laboratory, Systems and Computer Engineering Department, Carleton University. 09/12/2002, pages 10 - 42.
	V	Test Sequence Generation Scheme Satisfying the Completeness Criteria. HongSe Son, DaeHun Nyang, JinHo Park, SangYong Lim, ByungMoon Chin, JunWon Lee, and JooSeok Song. IEEE, 03/1997, pages 560 - 563.
	W	Testing Combinations of Parameters Made Easy. Gregory T. Daich IEEE, Software Technology Support Center (STSC), Science Applications Inteniational Corporation (SAIC). 07/2003, pages 379 - 384.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.